

ABSTRACT

A probe card includes a probe guide for holding a probe and a probe substrate stacked on the probe guide. The probe substrate has a first surface facing a tester head and a second surface facing the probe guide, and a through hole passing through from the first surface to the second surface is disposed therein. The probe guide abuts the probe substrate due to an inside of the through hole being evacuated while the probe substrate abuts the tester head by means of vacuum adsorption.

FIG. 1